

Notice of References Cited	Application/Control No. 10/588,238		Applicant(s)/Patent Under Reexamination ENDO ET AL.	
	Examiner MICHAEL R. VAUGHAN		Art Unit 2431	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,467,169 A	11-1995	Morikawa, Takeshi	399/366
*	B	US-6,230,268 B1	05-2001	Miwa et al.	713/176
*	C	US-2002/0061122 A1	05-2002	Fujihara et al.	382/100
*	D	US-2002/0149976 A1	10-2002	Sako, Yoichiro	365/200
*	E	US-2002/0176116 A1	11-2002	Rhoads et al.	358/405
*	F	US-6,522,769 B1	02-2003	Rhoads et al.	382/100
*	G	US-6,664,976 B2	12-2003	Lofgren et al.	345/634
*	H	US-6,748,485 B1	06-2004	Yokota et al.	711/112
*	I	US-6,813,369 B2	11-2004	Oki, Mitsuo	382/100
*	J	US-2005/0086326 A1	04-2005	Manning et al.	709/219
*	K	US-7,095,871 B2	08-2006	Jones et al.	382/100
*	L	US-7,171,020 B2	01-2007	Rhoads et al.	382/100
*	M	US-2007/0136597 A1	06-2007	Levy, Kenneth L.	713/176

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003085050 A	03-2003	Japan	TAKAHASHI, KENICHI	G06F 12/14
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.